Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/613,216	TOYOSHIMA ET AL.	
Examiner	Art Unit	
Quoc D. Tran	2614	

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Class	Subclass	Date	Examiner
379	88.19	8/6/2005	DN
	88.2		
	88.21		
	93.23		
	142.01		
	142.04		
	142.06		
	142.11		
379	142.12	8/6/2005	DN
379	142.13 to	8/7/2005	DN
	142.18		
	245		
379	354	8/7/2005	DN
Update	Previous searches	2/4/2006	DN

INTERFERENCE SEARCHED		
Subclass	Date	Examiner
search history	8/23/2006	QT
	Subclass search	Subclass Date

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST	8/6/2005	DN
EAST	8/7/2005	DN
EAST	8/11/2005	DN
Update EAST Benny Tieu (class 379 OSS and ACD)	8/22/2006	QT
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Applicant(s)/Patent under Reexamination
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Art Unit

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Class	Subclass	Date	Examiner
379	207.15	8/22/2006	QT
	210.01		
	211.02		
	214.01	-	
	218.01	•	
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